

ISSUED BY Shenzhen BALUN Technology Co., Ltd.

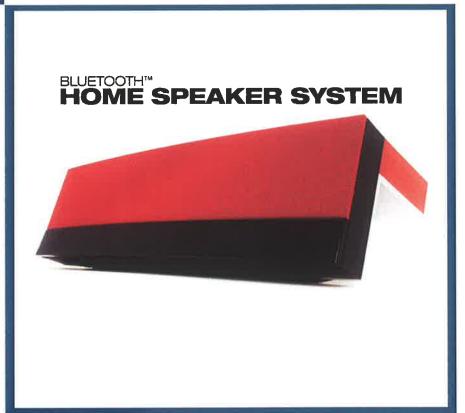


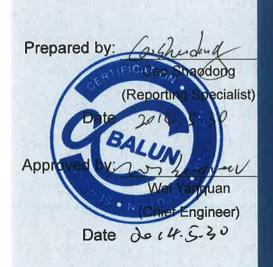
FOR

Bluetooth speaker 2.1

ISSUED TO Guoguang Electric Co., Ltd

No. 8 Jinghu Road, Xinhua Town, Huadu Region, Guangzhou, 510800 P. R. China





Model Name: Mercury Brand Name: N/A Test conclusion: PASS Test Date:

Report No.: BL-SZ1440034-401 EUT Type: Bluetooth speaker 2.1 Test Standard: 47 CFR Part 15 Subpart B FCC ID: 2AAP800005 2014.05.04-2014.05.10 Date of Issue: 2014.05.30

NOTE: This test report can be duplicated completely for the legal use with the approval of the applicant; it shall not be reproduced except in full, without the written approval of Shenzhen BALUN Technology Co., Ltd. BALUN Laboratory. Any objections should be raised within thirty days from the date of issue. To validate the report, please visit BALUN website.

Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong, P. R. China 518055

TEL: +86-755-66850100 FAX: +86-755-61824271 www.baluntek.com



Revision History

VersionIssue DateRevisionsRev. 012014.05.26Initial IssueRev. 012014.05.30The Second Issue

TABLE OF CONTENTS

1	GE	NERAL INFORMATION	. 4
	1.1	Identification of the Testing Laboratory	. 4
	1.2	Identification of the Responsible Testing Location	. 4
	1.3	Test Environment Condition	. 4
	1.4	Announce	. 5
2	PR	ODUCT INFORMATION	. 6
	2.1	Applicant	. 6
	2.2	Manufacturer	. 6
	2.3	General Description for Equipment under Test (EUT)	. 6
	2.4	Ancillary Equipment	. 7
3	SU	MMARY OF TEST RESULTS	. 8
	3.1	Test Standards	. 8
	3.2	Verdict	. 8
	3.3	Test Uncertainty	. 8
4	GE	NERAL TEST CONFIGURATIONS	. 9
	4.1	Test Environments	. 9
	4.2	Test Equipment List	. 9
	4.3	Test Enclosure list	10
	4.4	Test Configurations	10
	4.5	Test Setups	11
	4.6	Test Conditions	12
5	TES	ST ITEMS	13
	5.1	Emission Tests	13
Α	NNEX	A TEST RESULTS	15
	A.1	Radiated Emission	15
	A.2	Conducted Emission	18



ANNEX	X B TEST SETUP PHOTOS	20
B.1	Radiated Field Strength Measurement	20
B.2	Conducted Emission	21
ANNEX	X C EUT PHOTOS	22
C.1	Appearance of the EUT	22
C.2	Inside of the EUT	26



1 GENERAL INFORMATION

1.1 Identification of the Testing Laboratory

Company Name	Shenzhen BALUN Technology Co., Ltd.	
Address	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road,	
Address	Nanshan District, Shenzhen, Guangdong Province, P. R. China	
Phone Number	+86 755 6683 3402	
Fax Number	+86 755 6182 4271	

1.2 Identification of the Responsible Testing Location

Test Location	Shenzhen BALUN Technology Co., Ltd.	
Address	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road,	
Address	Nanshan District, Shenzhen, Guangdong Province, P. R. China	
	The laboratory has been listed by Industry Canada to perform	
	electromagnetic emission measurements. The recognition numbers of	
	test site are 11524A-1.	
	The laboratory has been listed by US Federal Communications	
	Commission to perform electromagnetic emission measurements. The	
	recognition numbers of test site are 832625.	
Accreditation Certificate	The laboratory has met the requirements of the IAS Accreditation Criteria	
	for Testing Laboratories (AC89), has demonstrated compliance with	
	ISO/IEC Standard 17025:2005. The accreditation certificate number is	
	TL-588.	
	The laboratory is a testing organization accredited by China National	
	Accreditation Service for Conformity Assessment (CNAS) according to	
	ISO/IEC 17025. The accreditation certificate number is L6791.	
	All measurement facilities used to collect the measurement data are	
Description	located at Block B, FL 1, Baisha Science and Technology Park, Shahe Xi	
Description	Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China	
	518055	

1.3 Test Environment Condition

Ambient Temperature	15 to 35°C
Ambient Relative Humidity	30 to 60%
Ambient Pressure	86 to 106kPa



1.4 Announce

- (1) The test report is invalid if not marked with the signatures of the persons responsible for preparing and approving the test report.
- (2) The test report is invalid if there is any evidence and/or falsification.
- (3) The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein.
- (4) This document may not be altered or revised in any way unless done so by BALUN and all revisions are duly noted in the revisions section.
- (5) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.



2 PRODUCT INFORMATION

2.1 Applicant

Applicant	Guoguang Electric Co., Ltd	
Addroso	No. 8 Jinghu Road, Xinhua Town, Huadu Region, Guangzhou, 510800 P.	
Address	R. China	

2.2 Manufacturer

Manufacturer	Guoguang Electric Co., Ltd
A ddraga	No. 8 Jinghu Road, Xinhua Town, Huadu Region, Guangzhou, 510800 P.
Address	R. China

2.3 General Description for Equipment under Test (EUT)

EUT Type	Bluetooth speaker 2.1	
Model Name	Mercury	
Hardware Version	N/A	
Software Version N/A		
Network and Wireless	BT 2.1+EDR	
connectivity	BI Z.ITEDR	
Display	N/A	
	The EUT is a Bluetooth speaker, it contains Bluetooth Module operating at	
About the Product	2.4GHz ISM band which supports Bluetooth 2.1+EDR. The EUT is	
	equipped with a USB power port, and an AUX port.	



2.4 Ancillary Equipment

	AC Adapter		
	Brand Name	N/A	
Ancillary Equipment 1	Model No	S048CU1500300	
	Serial No	(N/A. marked #1 by test site)	
	Rated Input	~ 100-240V, 1.5A Max, 50/60Hz	
	Rated Output	= 15V, 3000mA	



3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title	
1	FCC 47 CFR Part 15 Subpart	Unintentional Radiators	
ı	B (10-1-09 Edition)		
	ANSI C63.4-2009	American National Standard for Standard for Methods of	
		Measurement of Radio-Noise Emissions from Low-Voltage	
2		Electrical and Electronic Equipment in the Range of 9 kHz to	
		40 GHz	

3.2 Verdict

No.	Description	FCC Rule	Test Verdict	Result
1	Radiated Emission	15.109	PASS	Annex A .1
2	Conducted Emission, AC Ports	15.107	PASS	Annex A .2

3.3 Test Uncertainty

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Measurement	Value
Conducted emissions (9KHz-30MHz)	1.12dB
Radiated emissions (30MHz-1GHz)	2.11dB
Radiated emissions (1GHz-25GHz)	3.31dB



4 GENERAL TEST CONFIGURATIONS

4.1 Test Environments

Environment Parameter	Se	Selected Values During Tests						
Environment Parameter	Temperature	Voltage	Relative Humidity					
Normal Temperature,								
Normal Voltage	23°C~25°C	15.0V	50%-55%					
(NTNV)								

4.2 Test Equipment List

Radiated Emission Test										
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use				
EMI Receiver	ROHDE&SCHWARZ	ESRP	101036	2013.06.04	2014.06.03	\boxtimes				
Attenuator	KMW	20dB	110617091	2014.05.10	2015.05.09	\boxtimes				
Test Antenna- Loop(9kHz-30 MHz)	SCHWARZBECK	FMZB 1519	1519-037	2013.07.02	2014.07.01					
Test Antenna- Bi-Log(30MHz-3 GHz)	SCHWARZBECK	VULB 9163	9163-624	2013.07.03	2014.07.02					
Test Antenna- Horn(1-18 GHz)	SCHWARZBECK	BBHA 9120D	9120D-1148	2013.07.02	2014.07.01					
Test Antenna- Horn(15-26.5 GHz)	SCHWARZBECK	BBHA 9170	9170-305	2013.07.02	2014.07.01					
Anechoic Chamber	RAINFORD	9m*6m*6m	N/A	2013.10.07	2014.10.06	\boxtimes				

Conducted disturbance Test											
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use					
EMI Receiver	ROHDE&SCHWA RZ	ESRP	101036	2013.06.04	2014.06.03	\boxtimes					
LISN	SCHWARZBECK	NSLK 8127	8127-687	2013.06.04	2014.06.03	\boxtimes					
AMN	SCHWARZBECK	NNBM812 4	8124-509	2013.06.29	2014.06.28						
AMN	SCHWARZBECK	NNBM812 4	8124-510	2013.06.29	2014.06.28						
ISN	TESEQ	ISN T800	34449	2013.06.29	2014.06.28						



4.3 Test Enclosure list

Description	Manufacturer	Model	Serial No.	Length	Description	Use
PC	SOEYI	B123	N/A	N/A	N/A	\boxtimes
Printer	HP	DESKJET 1000	N/A	N/A	N/A	\boxtimes
Keyboard	logitech	Y-BP62a	N/A	N/A	N/A	\boxtimes
Mouse	logitech	M100	N/A	N/A	N/A	\boxtimes
USB disk	Kingston	N/A	N/A	N/A	N/A	
TF Card	Kingston	N/A	N/A	N/A	N/A	
VGA Cable	N/A	N/A	N/A	1 Em	Shielded	
VGA Cable	IN/A	IN/A	IN/A	1.5m	with core	
HDMI Cable	N/A	N/A	NI/A	1.5m	Shielded	
HDIVII Cable	IN/A	IN/A	N/A	1.3111	with core	
DVI Cable	N/A	N/A	N/A	1 Em	Shielded	
DVI Cable	IN/A	IN/A	IN/A	1.5m	with core	
IPhone	Apple	A1387	N/A	N/A	N/A	\boxtimes
Cement Resistor	N/A	N/A	N/A	N/A	2.5Ω,	\boxtimes
Cement Resistor	IN/A	IN/A	IN/A	IN/A	100W	

4.4 Test Configurations

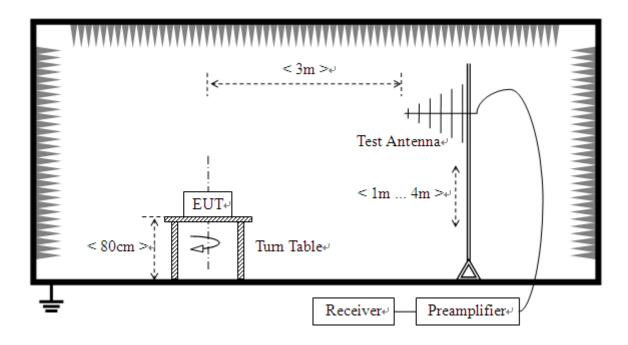
Test Configurations (TC) No.	Description
TC01	Bluetooth mode The EUT configuration of the emission tests is EUT + PC+ Charger+ iphone+ Cement Resistor. During the measurement, the EUT was powered by AC charger. A Bluetooth link was established between the EUT and the iPhone, the EUT was working normally as a music player. And the EUT was powered to the Cement Resistor through the USB cable.
TC02	The AUX mode The EUT configuration of the emission tests is EUT + Charger+ Iphone+ Cement Resistor. During the measurement, the EUT was powered by AC charger. And the EUT was connected with the Iphone through the AUX cable, working normally as a music player, the EUT was powered to the Cement Resistor through the USB cable.

Note: Based on client request, all normal using modes of the normal function were tested but only the worst test data of the worst mode is reported by this report.



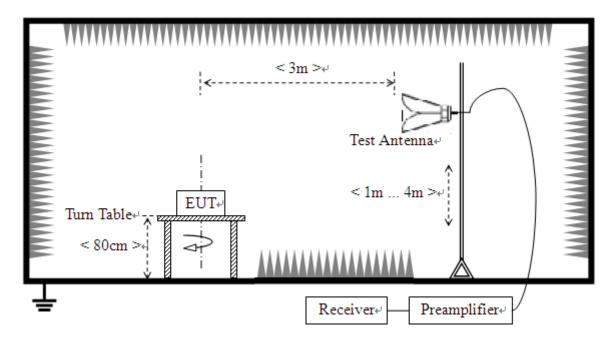
4.5 Test Setups

Test Setup 1



(For Radiated Emission Test (30MHz-1GHz))

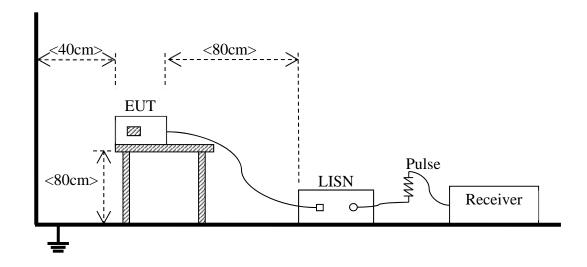
Test Setup 2



(For Radiated Emission Test (above 1GHz))



Test Setup 3



(For Conducted Emission, AC Ports Test)

4.6 Test Conditions

Test Case	Test Conditions				
	Test Env.	NTNV			
Radiated Emission	Test Setup	Test Setup 1&2			
	Test Configuration	TC01~TC02			
Conducted Emission AC	Test Env.	NTNV			
Conducted Emission, AC	Test Setup	Test Setup 3			
Ports	Test Configuration	TC01~TC02			



5 TEST ITEMS

5.1 Emission Tests

5.1.1 Radiated Emission

5.1.1.1 Limit

Frequency (MHz)	Field Strength (μV/m)	Measurement Distance (m)
0.009 - 0.490	2400/F(kHz)	300
0.490 - 1.705	24000/F(kHz)	30
1.705 - 30.0	30	30
30 - 88	100	3
88 - 216	150	3
216 - 960	200	3
Above 960	500	3

NOTE:

- 1) Field Strength ($dB\mu V/m$) = 20*log[Field Strength ($\mu V/m$)].
- 2) In the emission tables above, the tighter limit applies at the band edges.
- 3) For above 1000MHz, limit field strength of harmonics: 54dBuV/m@3m (AV) and 74dBuV/m@3m (PK)

5.1.1.2 Test Procedure

All Spurious Emission tests were performed in X, Y, Z axis direction. And only the worst axis test condition was recorded in this test report.

An initial pre-scan was performed in the chamber using the EMI Receiver in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by Bi-Log antenna with 2 orthogonal polarities.



5.1.2 Conducted Emission

5.1.2.1 Test Limit

Fraguency range (MHz)	Conducted I	Limit (dBµV)
Frequency range (MHz)	Quasi-peak	Average
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5 - 30	60	50

NOTE:

- 1) The limit is applicable to Class B ITE.
- 2) The lower limit shall apply at the band edges.
- 3) The limit decreases linearly with the logarithm of the frequency in the range 0.15 0.50MHz.

5.1.2.2 Test Procedure

The EUT is connected to the power mains through a LISN which provides $50\Omega/50\mu H$ of coupling impedance for the measuring instrument. The test frequency range is from 150kHz to 30MHz. The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels that are more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed.



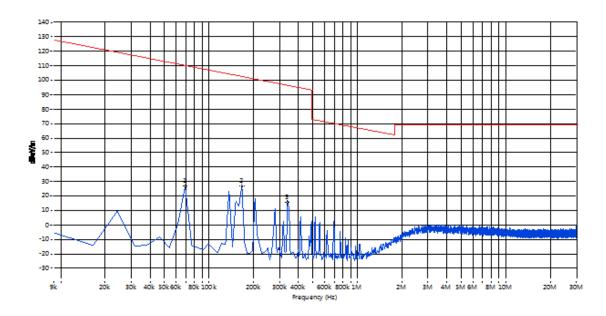
ANNEX A TEST RESULTS

A.1 Radiated Emission

Test Data

Note: The marked spikes near 2400MHz with circle should be ignored because they are Bluetooth carrier frequency.

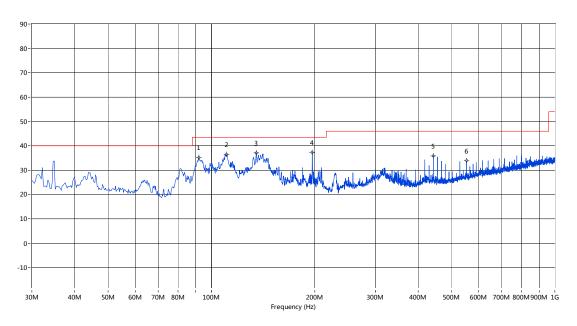
A.1.1 9kHz – 30MHz



Fre. (MHz)	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	Degree	Verdical
0.069	28.92				110.8			Pass
0.166	29.48				103.2			Pass
0.339	18.51				97.0			Pass

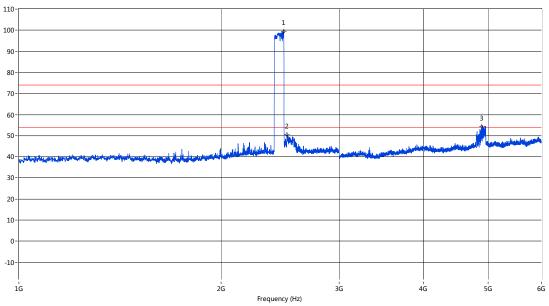


A.1.2 Test Antenna Vertical, 30MHz – 1GHz



Fre. (MHz)	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	Degree	Antenna	Verdical
91.822	35.20				43.5		162.8	Vertical	Pass
110.490	36.45				43.5		21.3	Vertical	Pass
134.976	37.08				43.5		270.3	Vertical	Pass
196.798	37.34				43.5		27.8	Vertical	Pass
442.632	35.92				46.0		38.1	Vertical	Pass
553.427	33.86				46.0		17.4	Vertical	Pass

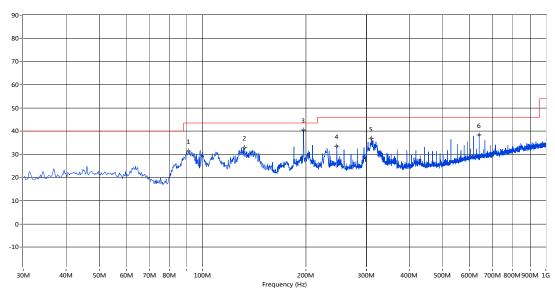
A.1.3 Test Antenna Vertical, 1GHz – 6GHz



Fre. (MHz)	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	Degree	Antenna	Verdical
2478.630	99.23						146.1	Vertical	
2508.123	50.37			74.0		54.0	317.9	Vertical	Pass
4954.011	54.44		46.95	74.0		54.0	344.5	Vertical	Pass

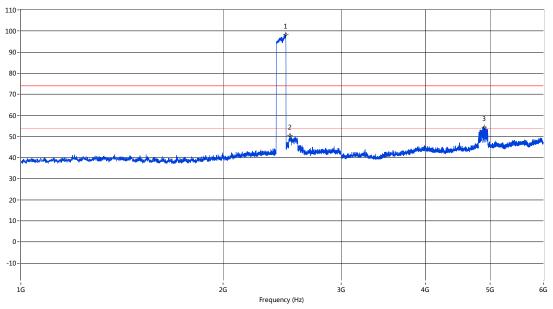


A.1.4 Test Antenna Horizontal, 30MHz – 1GHz



Fre. (MHz)	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	Degree	Antenna	Verdical
91.095	31.37				43.5		357.6	Horizontal	Pass
132.067	32.83				43.5		360.0	Horizontal	Pass
196.556	40.47				43.5		360.0	Horizontal	Pass
245.771	33.55				46.0		360.0	Horizontal	Pass
310.017	36.95				46.0		338.0	Horizontal	Pass
639.493	38.44				46.0		360.0	Horizontal	Pass

A.1.5 Test Antenna Horizontal, 1GHz – 6GHz



Fre. (MHz)	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	Degree	Antenna	Verdical
2479.130	98.24						343.0	Horizontal	
2518.120	50.40			74.0		54.0	348.9	Horizontal	Pass
4896.276	54.35		47.85	74.0		54.0	327.9	Horizontal	Pass



A.2 Conducted Emission

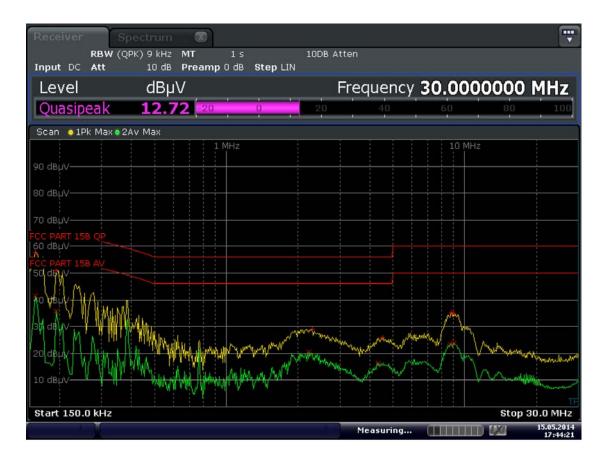
Test Data

No.	Frequency (MHz)	Measurement Level (dBuV)	Limit (dBuV)	Margin (dB)	Phase	Detector	Result
1	0.158	57.76	65.77	-8.01	L	QP	PASS
2	0.158	41.46	55.77	-14.31	L	AV	PASS
3	0.194	51.15	64.74	-13.59	L	QP	PASS
4	0.194	35.72	54.74	-19.02	L	AV	PASS
5	2.226	20.55	46.00	-25.45	L	AV	PASS
6	2.294	29.04	56.00	-26.96	L	QP	PASS
7	4.338	16.44	46.00	-29.56	L	AV	PASS
8	4.534	25.92	56.00	-30.08	L	QP	PASS
9	8.674	23.38	50.00	-26.62	L	AV	PASS
10	8.802	35.22	60.00	-24.78	L	QP	PASS
11	9.022	23.83	50.00	-26.17	L	AV	PASS
12	9.030	34.63	60.00	-25.37	L	QP	PASS
13	0.158	57.41	65.77	-8.36	N	QP	PASS
14	0.158	40.52	55.77	-15.25	N	AV	PASS
15	0.198	49.07	64.63	-15.56	N	QP	PASS
16	0.198	34.11	54.63	-20.52	N	AV	PASS
17	1.842	30.07	56.00	-25.93	N	QP	PASS
18	1.842	22.06	46.00	-23.94	N	AV	PASS
19	1.990	21.93	46.00	-24.07	N	AV	PASS
20	3.490	27.84	56.00	-28.16	N	QP	PASS
21	8.590	22.5	50.00	-27.50	N	AV	PASS
22	8.678	34.63	60.00	-25.37	N	QP	PASS
23	8.774	22.38	50.00	-27.62	N	AV	PASS
24	8.810	34.34	60.00	-25.66	N	QP	PASS

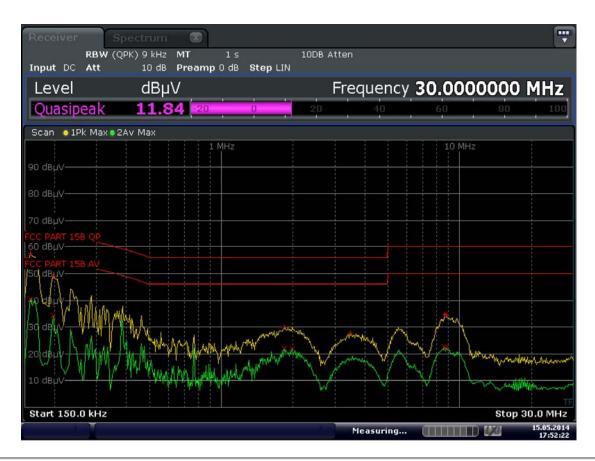


Test Plots

A.2.1 L Phase



A.2.2 N Phase



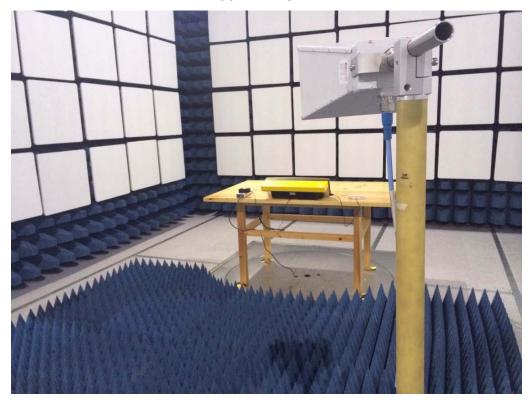


ANNEX B TEST SETUP PHOTOS

B.1 Radiated Field Strength Measurement



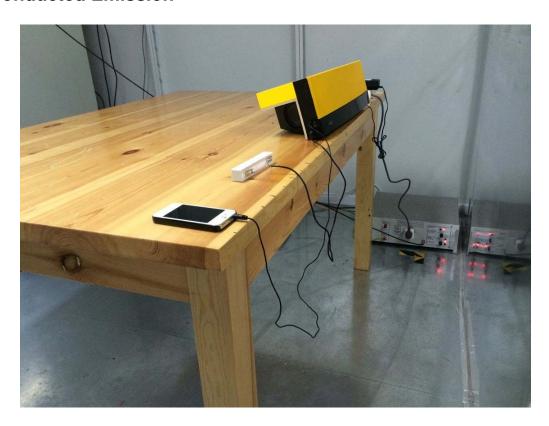
30MHz-1GHz



Above 1GHz



B.2 Conducted Emission





ANNEX C EUT PHOTOS

C.1 Appearance of the EUT

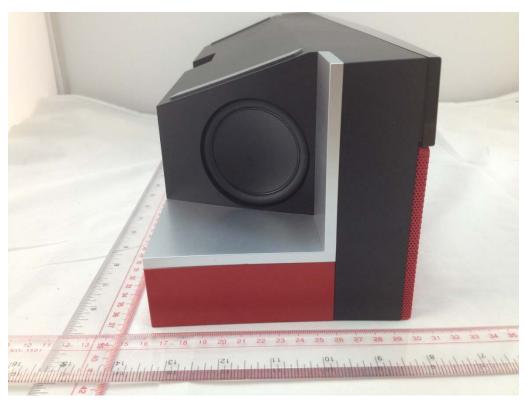


THE FRONT OF EUT

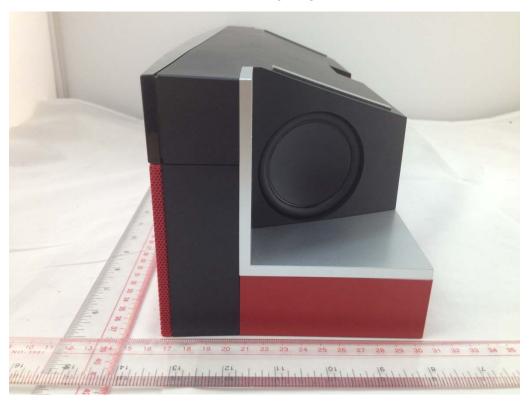


THE BACK OF EUT



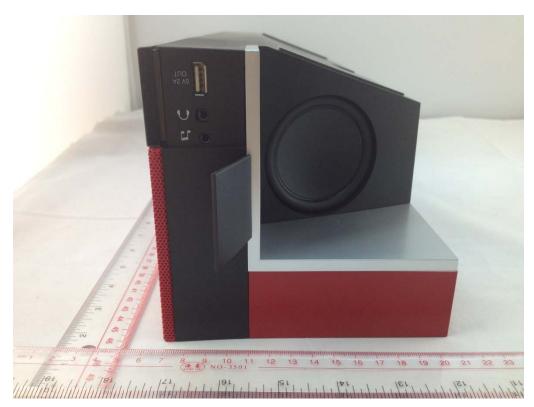


THE LEFT OF EUT



THE RIGHT OF EUT (1)





THE RIGHT OF EUT (2)



THE UP OF EUT





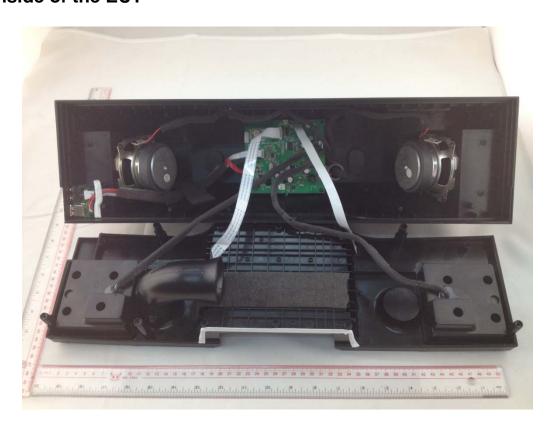
THE DOWN OF EUT



CHARGER



C.2 Inside of the EUT

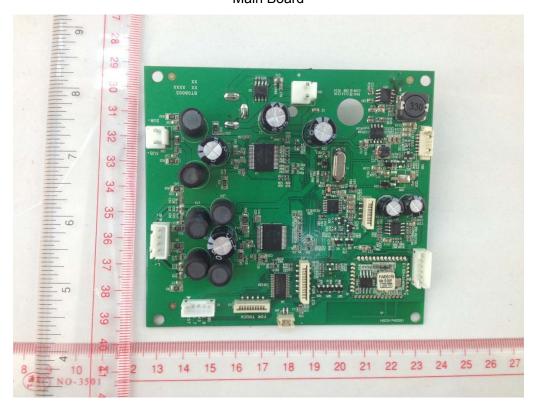






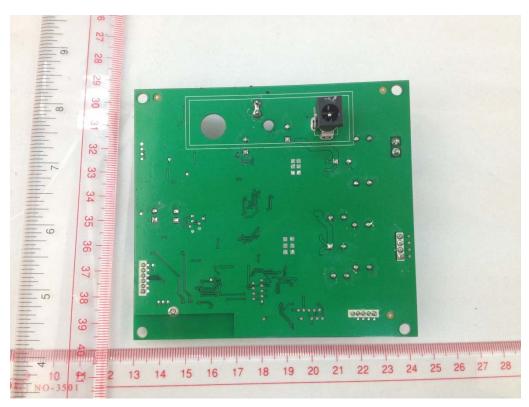


Main Board

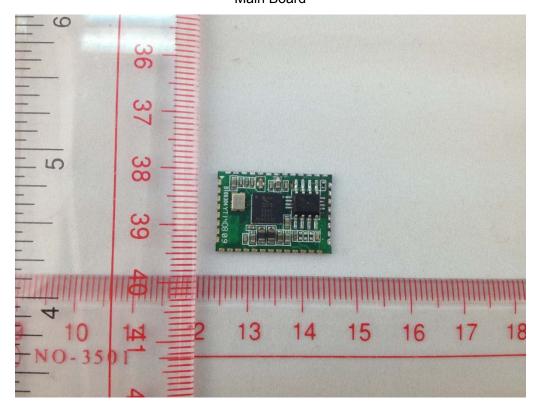


Main Board



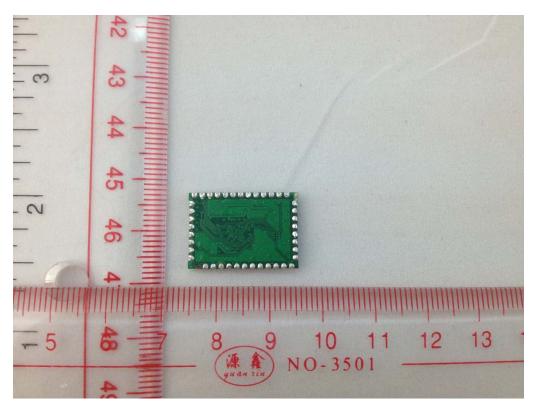


Main Board

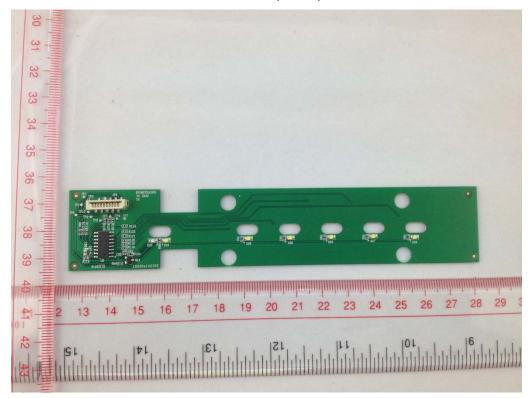


RF Board (FRONT)

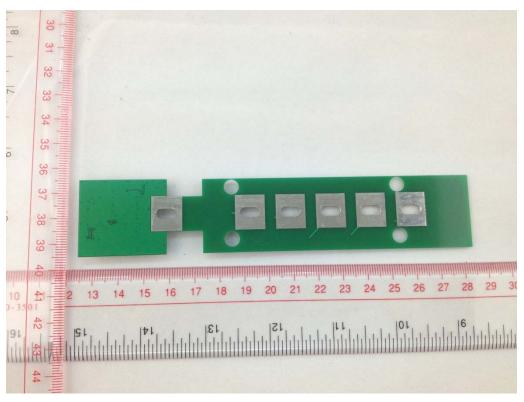


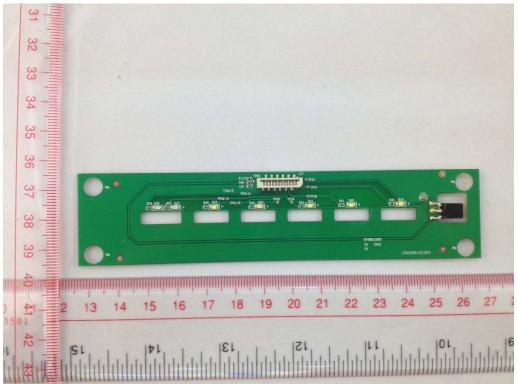


RF Board (BACK)

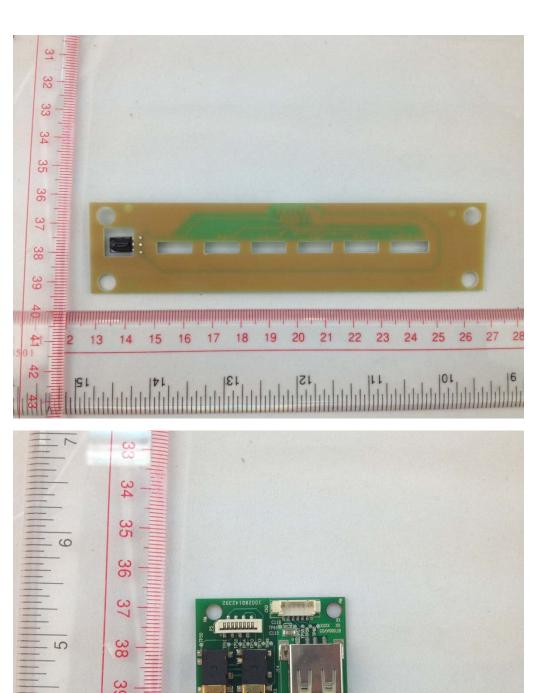






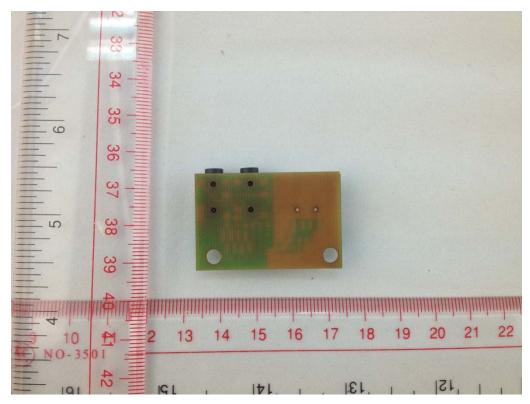






NO-3501





--END OF REPORT--